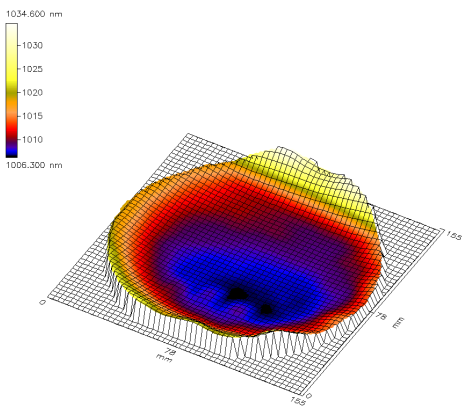


# FTR - Thin film sensor for high-resolution thickness measurement

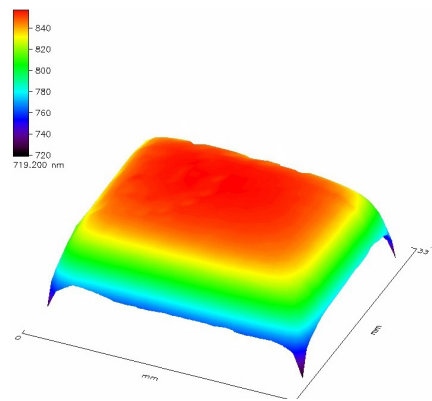


FTR sensor developed inhouse

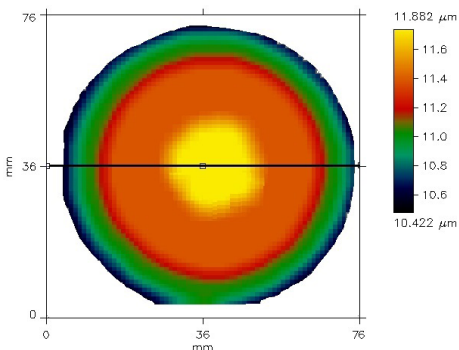
- > film thickness from a few ten nanometers up to the micrometer range
- > films, foils and coatings which are transparent for visible light
- > thickness of a thin single films and multi-layer systems
- > punctual thickness, 2D thickness profiles and 3D film thickness mapping
- > sub-nm thickness resolution and up to 5 nm lateral resolution
- > can be used in a multi-sensor configuration
- > optical, non-contact and non destructive
- > software including an expandable material data base
- > small, robust and wear-free measuring tool
- > very fast and extremely precise measurement



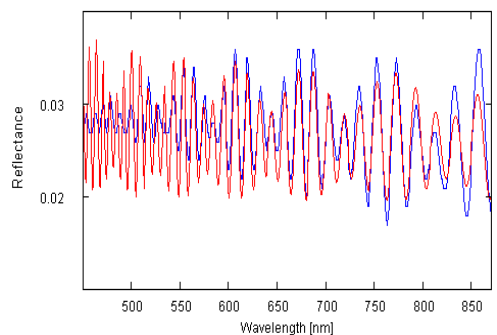
Film thickness mapping of a SiO<sub>2</sub> layer on a Si wafer



Film thickness mapping of a Si<sub>3</sub>N<sub>4</sub> coating on a Si substrate



Film thickness mapping of an epitaxial layer on a SiC wafer



Reflection spectrum of a SiO<sub>2</sub> layer on a Si wafer using a fit algorithm